INTEGRATED CIRCUITS

DATA SHEET

74AHC374; 74AHCT374

Octal D-type flip-flop; positive edge-trigger; 3-state

Product specification
Supersedes data of 1998 Dec 11
File under Integrated Circuits, IC06

1999 Sep 28

PHILIPS

Philips
Semiconductors

Octal D-type flip-flop; positive edge-trigger; 3-state

**74AHC374;
74AHCT374**

FEATURES

- ESD protection:
  HBM EIA/JESD22-A114-A
  exceeds 2000 V
  MM EIA/JESD22-A115-A
  exceeds 200 V
  CDM EIA/JESD22-C101
  exceeds 1 000 V
- Balanced propagation delays
- All inputs have Schmitt-trigger actions
- Inputs accepts voltages higher than V_{CC}
- Common 3-state output enable input
- I_{CC} category: MSI
- For AHC only:
  operates with CMOS input levels
- For AHCT only:
  operates with TTL input levels
- Specified from
  -40 to $+85$ and $+125$ °C.

DESCRIPTION

The 74AHC/AHCT374 are high-speed Si-gate CMOS devices and are pin compatible with low power Schottky TTL (LSTTL). They are specified in compliance with JEDEC standard No. 7A.

The 74AHC/AHCT374 are octal D-type flip-flops featuring separate D-type inputs for each flip-flop and 3-state outputs for bus oriented applications. A clock (CP) and an output enable ($\overline{OE}$) input are common to all flip-flops.

The 8 flip-flops will store the state of their individual D-inputs that meet the set-up and hold times requirements on the LOW-to-HIGH CP transition.

When $\overline{OE}$ is LOW the contents of the 8 flip-flops are available at the outputs. When $\overline{OE}$ is HIGH, the outputs go to the high-impedance OFF-state. Operation of the $\overline{OE}$ input does not affect the state of the flip-flops.

The '374' is functionally identical to the '534', but has non-inverting outputs.

QUICK REFERENCE DATA

GND = 0 V; T_{amb} = 25 °C; t_r = $t_f \leq$ 3.0 ns.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL		UNIT
			AHC	AHCT	
t_{PHL}/t_{PLH}	propagation delay; CP to Q_n	C_L = 15 pF; V_{CC} = 5 V	3.5	5.0	ns
f_{max}	maximum clock frequency	C_L = 15 pF; V_{CC} = 5 V	50	–	MHz
C_I	input capacitance	V_I = V_{CC} or GND	3.0	3.0	pF
C_O	output capacitance		4.0	4.0	pF
C_{PD}	power dissipation capacitance	C_L = 50 pF; f = 1 MHz; notes 1 and 2	10	12	pF

Notes

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

   $P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

   f_i = input frequency in MHz;

   f_o = output frequency in MHz;

   $\Sigma (C_L \times V_{CC}^2 \times f_o)$ = sum of outputs;

   C_L = output load capacitance in pF;

   V_{CC} = supply voltage in Volts.

2. The condition is V_I = GND to V_{CC}.

Octal D-type flip-flop; positive edge-trigger; 3-state

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FUNCTION TABLE

See note 1.

OPERATING MODES	INPUTS			INTERNAL FLIP-FLOPS	OUTPUTS
	$\overline{OE}$	CP	D_n		Q_0 to Q_7
Load and read register	L	↑	I	L	L
	L	↑	h	H	H
Load register and disable outputs	H	↑	I	L	Z
	H	↑	h	H	Z

Note

1. H = HIGH voltage level;

    h = HIGH voltage level one set-up time prior to the LOW-to-HIGH CP transition;

    L = LOW voltage level;

    I = LOW voltage level one set-up time prior to the LOW-to-HIGH CP transition;

    X = don't care;

    Z = high-impedance OFF-state;

    ↑ = LOW-to-HIGH CP transition.

ORDERING INFORMATION

OUTSIDE NORTH AMERICA	NORTH AMERICA	PACKAGES			
		PINS	PACKAGE	MATERIAL	CODE
74AHC374D	74AHC374D	20	SO	plastic	SOT163-1
74AHC374PW	74AHC374PW DH	20	TSSOP	plastic	SOT360-1
74AHCT374D	74AHCT374D	20	SO	plastic	SOT163-1
74AHCT374PW	7AHCT374PW DH	20	TSSOP	plastic	SOT360-1

PINNING

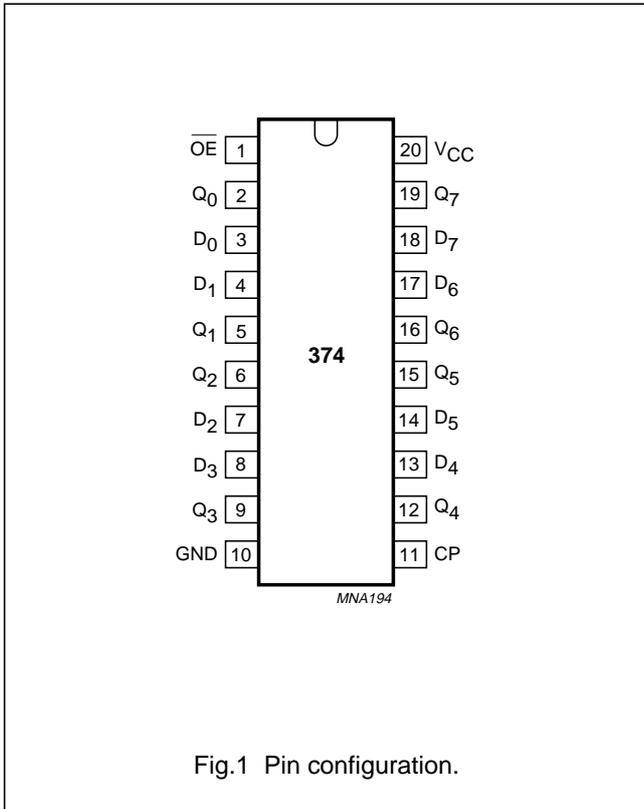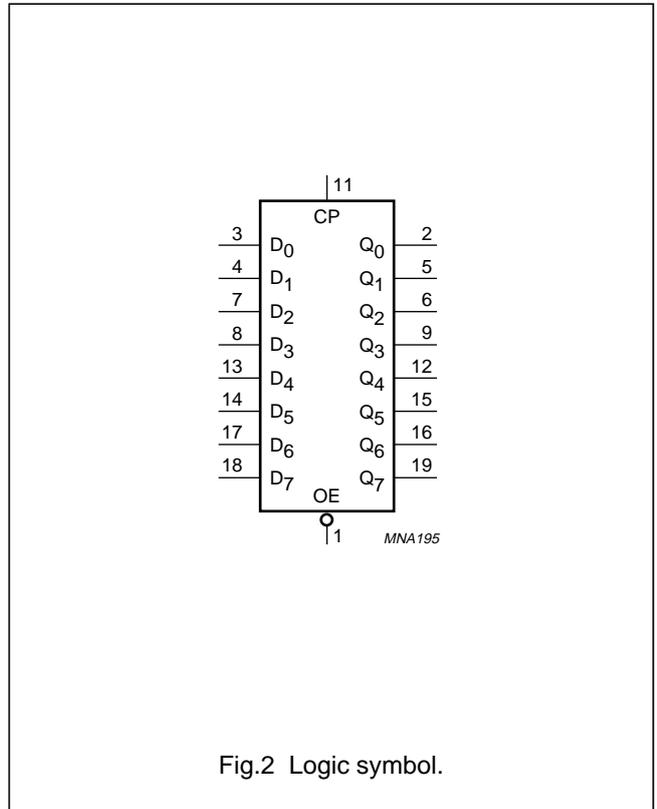| PIN	SYMBOL	DESCRIPTION
1	$\overline{OE}$	3-state output enable input (active LOW)
2, 5, 6, 9, 12, 15, 16 and 19	Q_0 to Q_7	3-state flip-flop outputs
3, 4, 7, 8, 13, 14, 17 and 18	D_0 to D_7	data inputs
10	GND	ground (0 V)
11	CP	clock input (LOW-to-HIGH, edge triggered)
20	V_{CC}	DC supply voltage

Octal D-type flip-flop; positive edge-trigger; 3-state
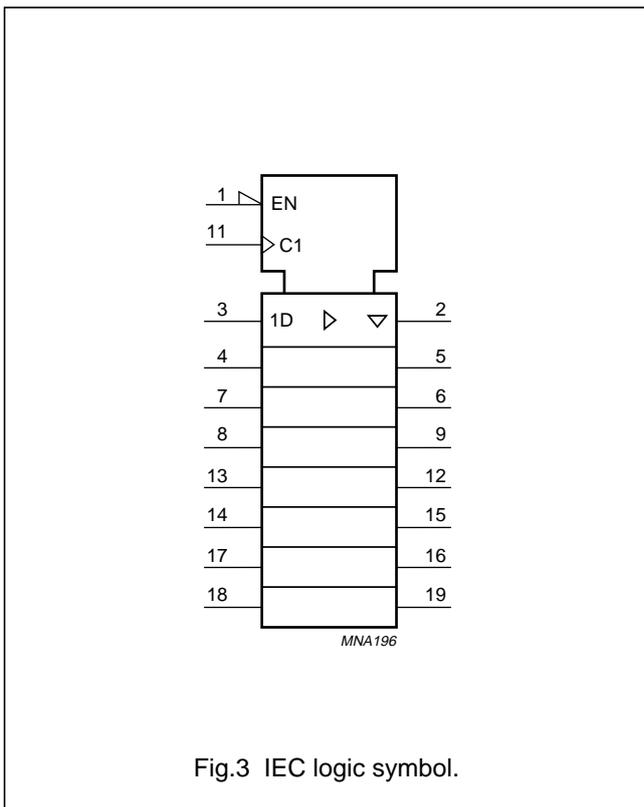
Fig.1 Pin configuration.

Fig.2 Logic symbol.

Fig.3 IEC logic symbol.
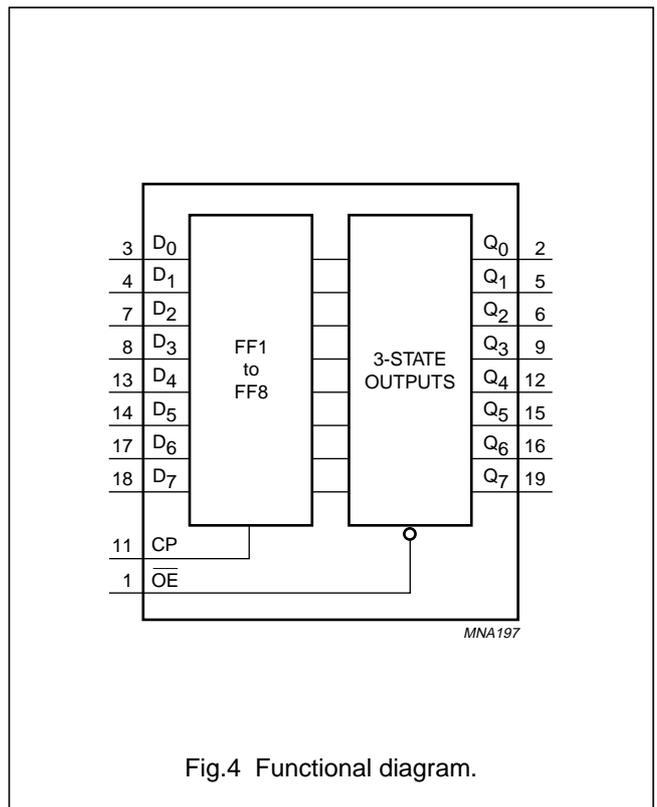
Fig.4 Functional diagram.

Octal D-type flip-flop; positive edge-trigger; 3-state

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Fig.5 Logic diagram.
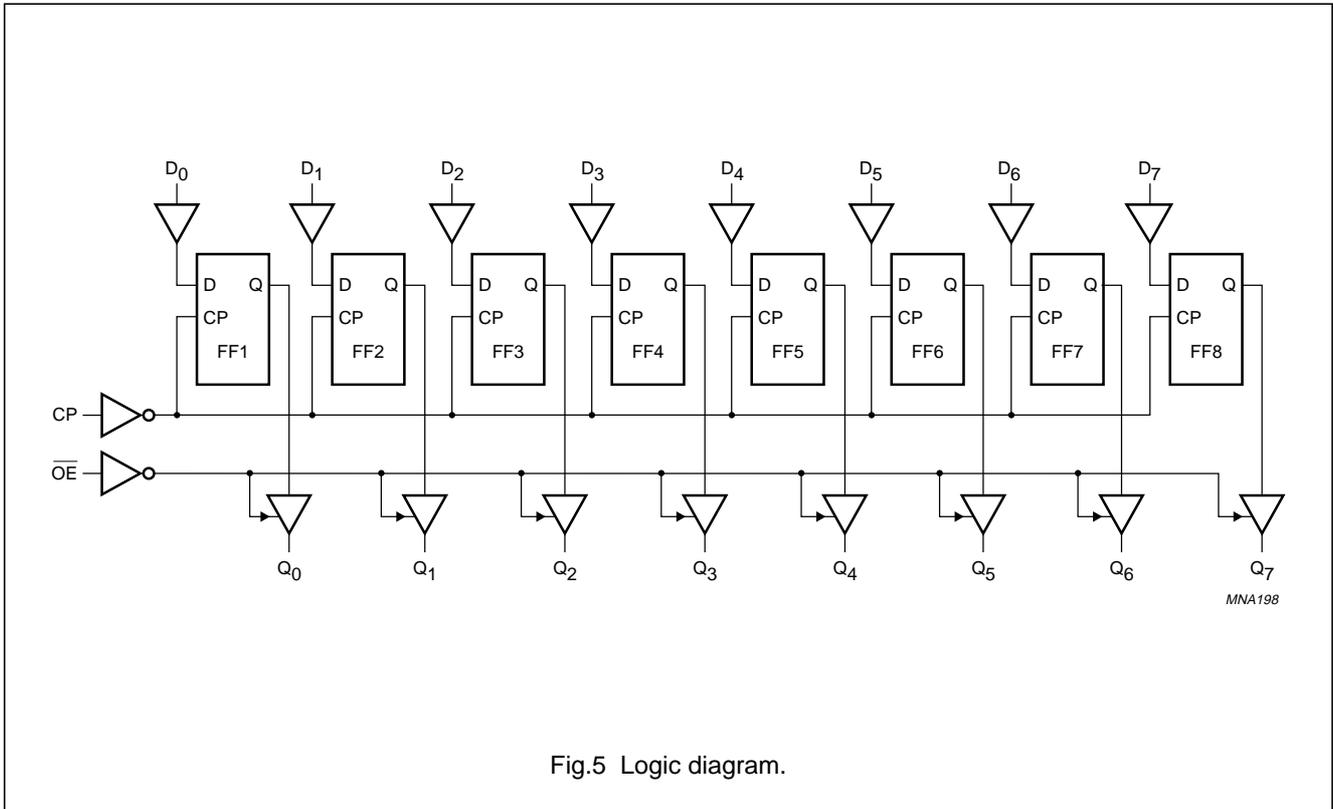
RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	74AHC			74AHCT			UNIT
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
V_{CC}	DC supply voltage		2.0	5.0	5.5	4.5	5.0	5.5	V
V_I	input voltage		0	–	5.5	0	–	5.5	V
V_O	output voltage		0	–	V_{CC}	0	–	V_{CC}	V
T_{amb}	operating ambient temperature range	see DC and AC characteristics per device	−40	+25	+85	−40	+25	+85	°C
			−40	+25	+125	−40	+25	+125	°C
t_r, t_f ($\Delta t/\Delta f$)	input rise and fall rates	V_{CC} = 3.3 V ±0.3 V	–	–	100	–	–	–	ns/V
		V_{CC} = 5 V ±0.5 V	–	–	20	–	–	20	

Octal D-type flip-flop; positive edge-trigger; 3-state

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CC}	DC supply voltage		−0.5	+7.0	V
V_I	input voltage range		−0.5	+7.0	V
I_{IK}	DC input diode current	$V_I < -0.5$ V; note 1	−	−20	mA
I_{OK}	DC output diode current	$V_O < -0.5$ V or $V_O > V_{CC} + 0.5$ V; note 1	−	±20	mA
I_O	DC output source or sink current	-0.5 V $< V_O < V_{CC} + 0.5$ V	−	±25	mA
I_{CC}	DC V_{CC} or GND current		−	±75	mA
T_{stg}	storage temperature range		−65	+150	°C
P_D	power dissipation per package	for temperature range: −40 to +125 °C; note 2	−	500	mW

Notes

1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. For SO packages: above 70 °C the value of P_D derates linearly with 8 mW/K.

   For TSSOP packages: above 60 °C the value of P_D derates linearly with 5.5 mW/K.

Octal D-type flip-flop; positive edge-trigger; 3-state

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DC CHARACTERISTICS

74AHC family

Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		T_{amb} (°C)							UNIT
		OTHER	V_{CC} (V)	25			−40 to +85		−40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V_{IH}	HIGH-level input voltage		2.0	1.5	–	–	1.5	–	1.5	–	V
			3.0	2.1	–	–	2.1	–	2.1	–	
			5.5	3.85	–	–	3.85	–	3.85	–	
V_{IL}	LOW-level input voltage		2.0	–	–	0.5	–	0.5	–	0.5	V
			3.0	–	–	0.9	–	0.9	–	0.9	
			5.5	–	–	1.65	–	1.65	–	1.65	
V_{OH}	HIGH-level output voltage; all outputs	$V_I = V_{IH}$ or V_{IL}; $I_O = -50\ \mu A$	2.0	1.9	2.0	–	1.9	–	1.9	–	V
			3.0	2.9	3.0	–	2.9	–	2.9	–	
			4.5	4.4	4.5	–	4.4	–	4.4	–	
	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}; $I_O = -4.0$ mA	3.0	2.58	–	–	2.48	–	2.40	–	V
		$V_I = V_{IH}$ or V_{IL}; $I_O = -8.0$ mA	4.5	3.94	–	–	3.8	–	3.70	–	
V_{OL}	LOW-level output voltage; all outputs	$V_I = V_{IH}$ or V_{IL}; $I_O = 50\ \mu A$	2.0	–	0	0.1	–	0.1	–	0.1	V
			3.0	–	0	0.1	–	0.1	–	0.1	
			4.5	–	0	0.1	–	0.1	–	0.1	
	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}; $I_O = 4$ mA	3.0	–	–	0.36	–	0.44	–	0.55	V
		$V_I = V_{IH}$ or V_{IL}; $I_O = 8$ mA	4.5	–	–	0.36	–	0.44	–	0.55	
I_I	input leakage current	$V_I = V_{CC}$ or GND	5.5	–	–	0.1	–	1.0	–	2.0	μA
I_{OZ}	3-state output OFF current	$V_I = V_{IH}$ or V_{IL}; $V_O = V_{CC}$ or GND	5.5	–	–	±0.25	–	±2.5	–	±10.0	μA
I_{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	5.5	–	–	4.0	–	40	–	80	μA
C_I	input capacitance		–	–	3	10	–	10	–	10	pF

Octal D-type flip-flop; positive edge-trigger; 3-state

74AHCT family

Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		T_{amb} (°C)							UNIT
		OTHER	V_{CC} (V)	25			−40 to +85		−40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V_{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	–	–	2.0	–	2.0	–	V
V_{IL}	LOW-level input voltage		4.5 to 5.5	–	–	0.8	–	0.8	–	0.8	V
V_{OH}	HIGH-level output voltage; all outputs	$V_I = V_{IH}$ or V_{IL}; $I_O = -50$ μA	4.5	4.4	4.5	–	4.4	–	4.4	–	V
	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}; $I_O = -8.0$ mA	4.5	3.94	–	–	3.8	–	3.70	–	V
V_{OL}	LOW-level output voltage; all outputs	$V_I = V_{IH}$ or V_{IL}; $I_O = 50$ μA	4.5	–	0	0.1	–	0.1	–	0.1	V
	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}; $I_O = 8$ mA	4.5	–	–	0.36	–	0.44	–	0.55	V
I_I	input leakage current	$V_I = V_{IH}$ or V_{IL}	5.5	–	–	0.1	–	1.0	–	2.0	μA
I_{OZ}	3-state output OFF current	$V_I = V_{IH}$ or V_{IL}; $V_O = V_{CC}$ or GND per input pin; other inputs at V_{CC} or GND; $I_O = 0$	5.5	–	–	±0.25	–	±2.5	–	±10.0	μA
I_{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	5.5	–	–	4.0	–	40	–	80	μA
ΔI_{CC}	additional quiescent supply current per input pin	$V_I = V_{CC} - 2.1$ V other inputs at V_{CC} or GND; $I_O = 0$	4.5 to 5.5	–	–	1.35	–	1.5	–	1.5	mA
C_I	input capacitance		–	–	3	10	–	10	–	10	pF

Octal D-type flip-flop; positive edge-trigger; 3-state

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AC CHARACTERISTICS

Type 74AHC374

GND = 0 V; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS		T_{amb} (°C)							UNIT
		WAVEFORMS	C_L	25			−40 to +85		−40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V_{CC} = 3.0 to 3.6 V; note 1											
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	15 pF	–	6.4	12.7	1.0	15.0	1.0	16.0	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	5.5	11.0	1.0	13.0	1.0	14.0	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	5.6	10.5	1.0	12.5	1.0	13.0	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		80	130	–	70	–	70	–	MHz
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	50 pF	–	8.4	16.2	1.0	18.5	1.0	20.5	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	7.3	14.5	1.0	16.5	1.0	18.0	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	9.4	14.0	1.0	16.0	1.0	17.5	ns
t_W	clock pulse width HIGH or LOW	see Figs 6 and 9		5.0	–	–	5.5	–	5.5	–	ns
t_{su}	set-up time D_n to CP	see Figs 8 and 9		4.5	–	–	4.0	–	4.0	–	ns
t_h	hold time D_n to CP			2.0	–	–	2.0	–	2.0	–	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		55	85	–	50	–	50	–	MHz

Octal D-type flip-flop; positive edge-trigger; 3-state

SYMBOL	PARAMETER	TEST CONDITIONS		T_{amb} (°C)							UNIT
		WAVEFORMS	C_L	25			−40 to +85		−40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V_{CC} = 4.5 to 5.5 V; note 2											
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	15 pF	–	4.4	8.1	1.0	9.5	1.0	10.0	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	3.9	7.6	1.0	9.0	1.0	9.5	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	4.2	6.8	1.0	8.0	1.0	8.5	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		130	185	–	110	–	110	–	MHz
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	50 pF	–	5.7	10.1	1.0	11.5	1.0	12.5	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	5.2	9.6	1.0	11	1.0	12.0	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	6.4	8.8	1.0	10.0	1.0	11.0	ns
t_W	clock pulse width HIGH or LOW	see Figs 6 and 9		5.0	–	–	5.0	–	5.0	–	ns
t_{su}	set-up time D_n to CP	see Figs 8 and 9		3.0	–	–	3.0	–	3.0	–	ns
t_h	hold time D_n to CP			2.0	–	–	2.0	–	2.0	–	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		85	120	–	75	–	75	–	MHz

Notes

1. Typical values at V_{CC} = 3.3 V.

2. Typical values at V_{CC} = 5.0 V.

Octal D-type flip-flop; positive edge-trigger; 3-state

Type 74AHCT374

GND = 0 V; $t_r = t_f \le 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS		T_{amb} (°C)							UNIT
		WAVEFORMS	C_L	25			−40 to +85		−40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V_{CC} = 4.5 to 5.5 V; note 1											
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	15 pF	–	4.3	9.4	1.0	10.5	1.0	12.0	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	3.5	10.2	1.0	11.5	1.0	13.0	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	3.6	10.2	1.0	11.0	1.0	13.0	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		90	140	–	80	–	80	–	MHz
t_{PHL}/t_{PLH}	propagation delay CP to Q_n	see Figs 6, 8 and 9	50 pF	–	5.6	10.4	1.0	11.5	1.0	13.0	ns
t_{PZH}/t_{PZL}	propagation delay $\overline{OE}$ to Q_n	see Figs 7 and 9		–	4.8	11.2	1.0	12.5	1.0	14.0	ns
t_{PHZ}/t_{PLZ}	propagation delay $\overline{OE}$ to Q_n			–	5.7	11.2	1.0	12.0	1.0	14.0	ns
t_W	clock pulse width HIGH or LOW	see Figs 6 and 9		6.5	–	–	6.5	–	6.5	–	ns
t_{su}	set-up time D_n to CP	see Figs 8 and 9		2.5	–	–	2.5	–	2.5	–	ns
t_h	hold time D_n to CP			2.5	–	–	2.5	–	2.5	–	ns
f_{max}	maximum clock pulse frequency	see Figs 6 and 9		85	130	–	75	–	75	–	MHz

Note

1. Typical values at V_{CC} = 5.0 V.

AC WAVEFORMS

FAMILY	V_I INPUT REQUIREMENTS	$V_M{}^{(1)}$ INPUT	$V_M{}^{(1)}$ OUTPUT
AHC	GND to V_{CC}	50% V_{CC}	50% V_{CC}
AHCT	GND to 3.0 V	1.5 V	50% V_{CC}

Fig.6 The clock (CP) to output (Q_n) propagation delays.
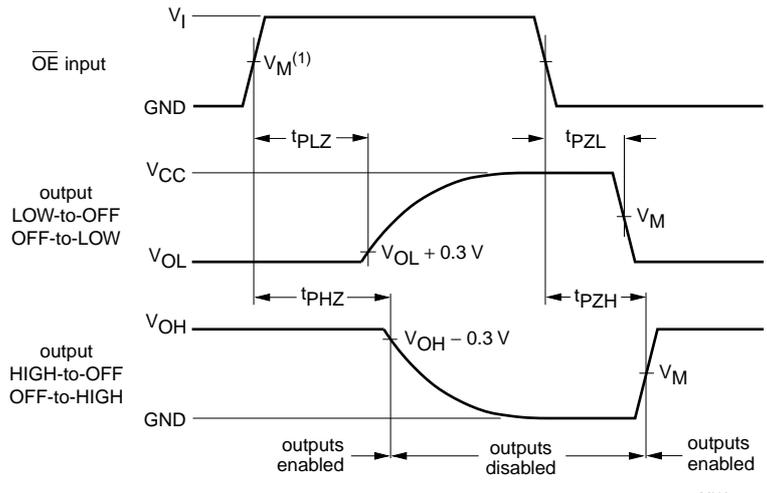
FAMILY	V_I INPUT REQUIREMENTS	$V_M{}^{(1)}$ INPUT	$V_M{}^{(1)}$ OUTPUT
AHC	GND to V_{CC}	50% V_{CC}	50% V_{CC}
AHCT	GND to 3.0 V	1.5 V	50% V_{CC}

Fig.7 The 3-state enable and disable times.

Octal D-type flip-flop; positive edge-trigger; 3-state
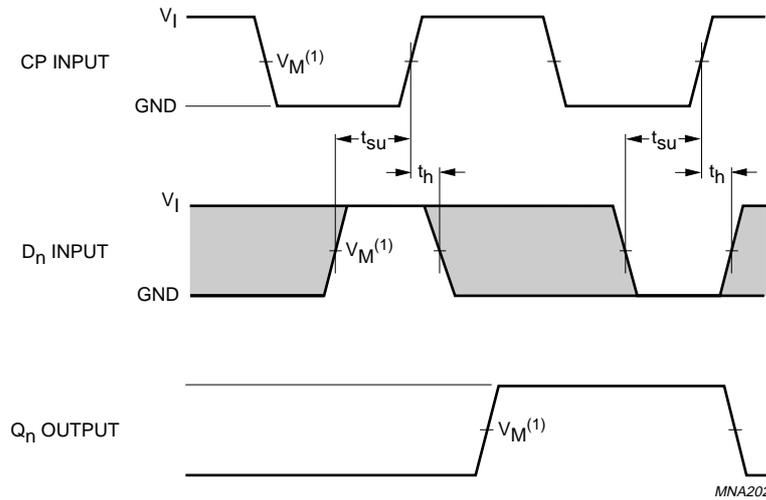
74AHC374;
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FAMILY	V_I INPUT REQUIREMENTS	$V_M^{(1)}$ INPUT	$V_M^{(1)}$ OUTPUT
AHC	GND to V_{CC}	50% V_{CC}	50% V_{CC}
AHCT	GND to 3.0 V	1.5 V	50% V_{CC}

The shaded areas indicate when the input is permitted to change for predicable output performance.

Fig.8 The data set-up and hold times for D_n input.
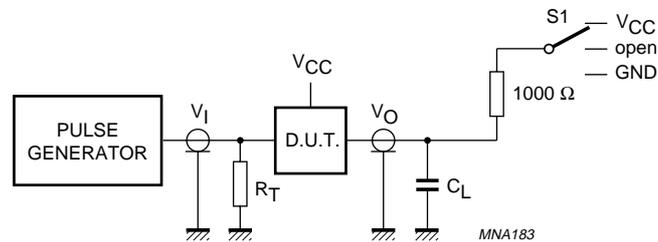
TEST	S_1
t_{PLH}/t_{PHL}	open
t_{PLZ}/t_{PZL}	V_{CC}
t_{PHZ}/t_{PZH}	GND

Fig.9 Load circuitry for switching times.

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PACKAGE OUTLINES

SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1

pin 1 index

detail X

0   5   10 mm
scale
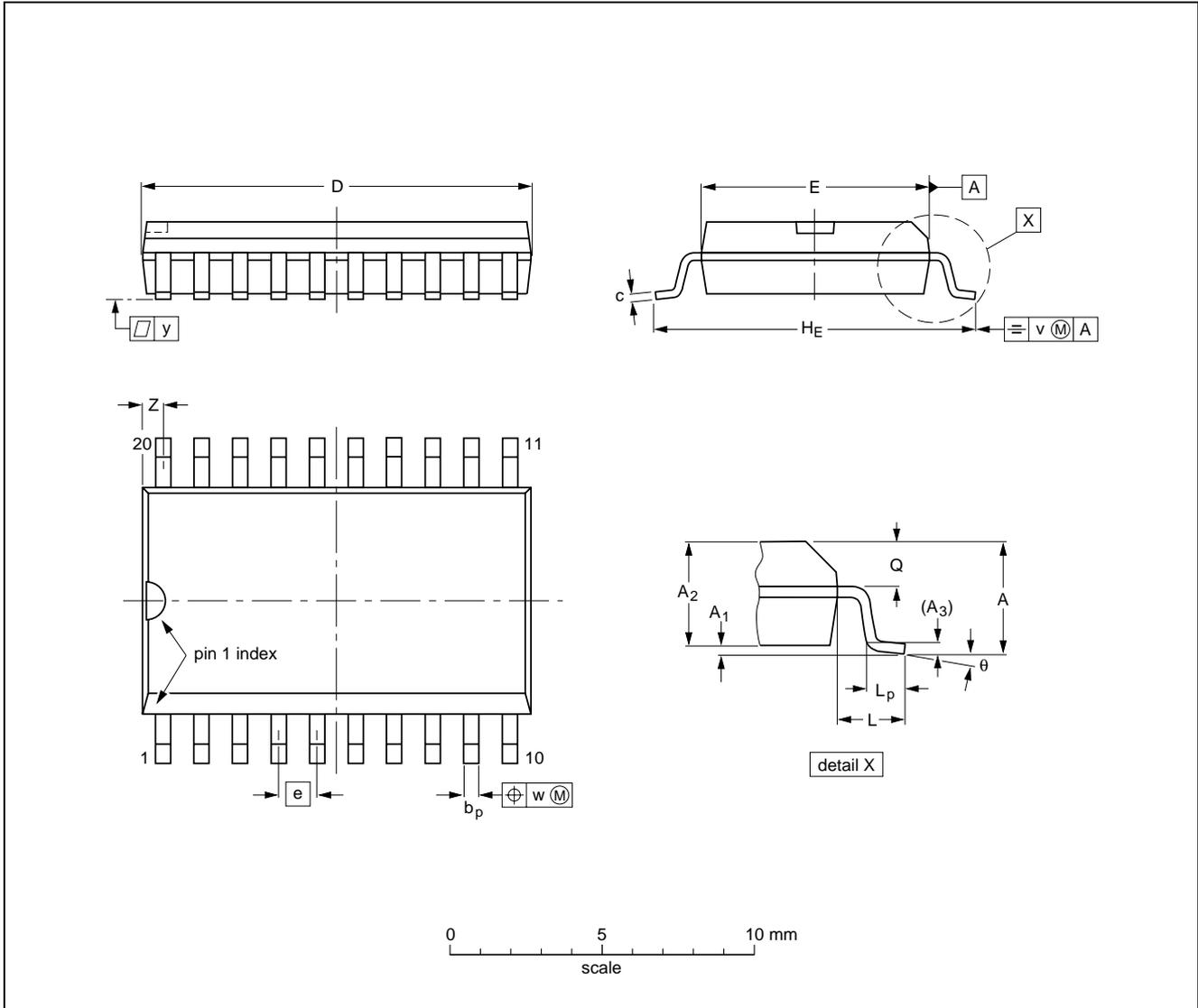
DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A₁	A₂	A₃	bₚ	c	D(1)	E(1)	e	H_E	L	Lₚ	Q	v	w	y	Z(1)	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	13.0 12.6	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8º 0º
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.51 0.49	0.30 0.29	0.050	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT163-1	075E04	MS-013AC				~~95-01-24~~ 97-05-22

Octal D-type flip-flop; positive edge-trigger; 3-state

74AHC374;
74AHCT374

TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm

SOT360-1

pin 1 index

detail X

0   2.5   5 mm
scale
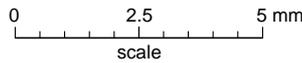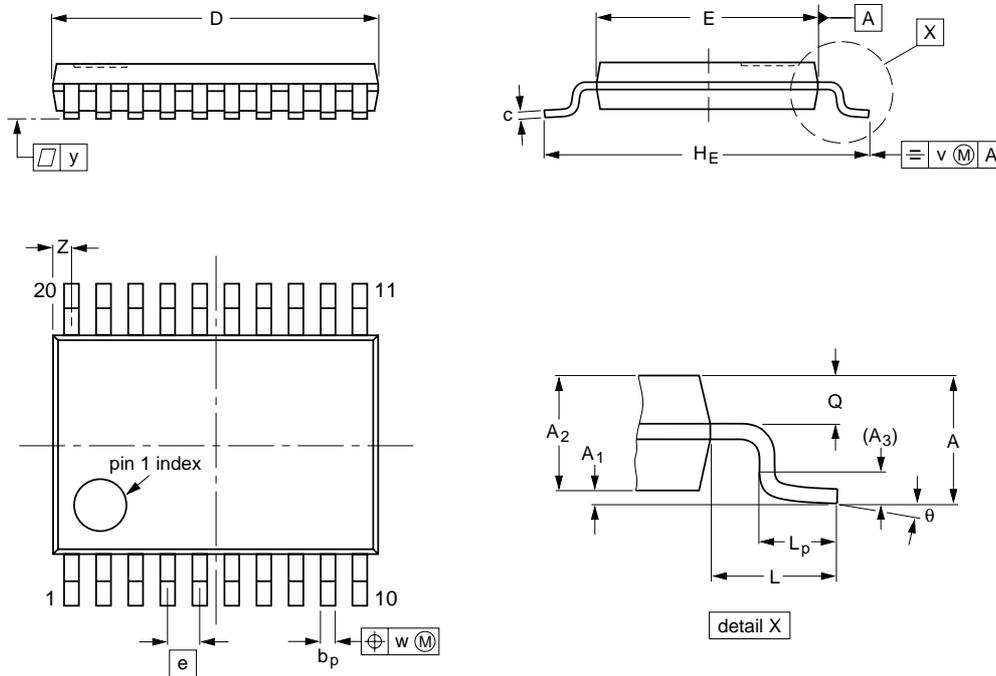
DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A₁	A₂	A₃	bₚ	c	D⁽¹⁾	E⁽²⁾	e	Hₑ	L	Lₚ	Q	v	w	y	Z⁽¹⁾	θ
mm	1.10	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1.0	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT360-1		MO-153AC				~~93-06-16~~ 95-02-04

SOLDERING

Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering is not always suitable for surface mount ICs, or for printed-circuit boards with high population densities. In these situations reflow soldering is often used.

Reflow soldering

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several methods exist for reflowing; for example, infrared/convection heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 to 250 °C. The top-surface temperature of the packages should preferable be kept below 230 °C.

Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.

- For packages with leads on two sides and a pitch (e):
  - larger than or equal to 1.27 mm, the footprint longitudinal axis is **preferred** to be parallel to the transport direction of the printed-circuit board;
  - smaller than 1.27 mm, the footprint longitudinal axis **must** be parallel to the transport direction of the printed-circuit board.

  The footprint must incorporate solder thieves at the downstream end.

- For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time is 4 seconds at 250 °C.
A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320 °C.

Octal D-type flip-flop; positive edge-trigger; 3-state

74AHC374;
74AHCT374

Suitability of surface mount IC packages for wave and reflow soldering methods

PACKAGE	SOLDERING METHOD	
	WAVE	**REFLOW**(1)
BGA, SQFP	not suitable	suitable
HLQFP, HSQFP, HSOP, HTQFP, HTSSOP, SMS	not suitable(2)	suitable
PLCC(3), SO, SOJ	suitable	suitable
LQFP, QFP, TQFP	not recommended(3)(4)	suitable
SSOP, TSSOP, VSO	not recommended(5)	suitable

Notes

1. All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the *"Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods"*.

2. These packages are not suitable for wave soldering as a solder joint between the printed-circuit board and heatsink (at bottom version) can not be achieved, and as solder may stick to the heatsink (on top version).

3. If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.

4. Wave soldering is only suitable for LQFP, TQFP and QFP packages with a pitch (e) equal to or larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.

5. Wave soldering is only suitable for SSOP and TSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.

DEFINITIONS

Data sheet status	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
Limiting values	
Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.	
Application information	
Where application information is given, it is advisory and does not form part of the specification.	

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